


<b>Search Notes</b>  	<b>Application/Control No.</b>  10580087	<b>Applicant(s)/Patent Under Reexamination</b>  PECH ET AL.
	<b>Examiner</b>  Kruer, Stefan	<b>Art Unit</b>  3654

SEARCHED			
Class	Subclass	Date	Examiner
242	374, 379.1, 383.2	01/07/2008	SHK
297	480		
280	806		
B60R	22/46		
Updated above		5/19/2008	SHK
242	390.6, 390.9	5/20/2008	

SEARCH NOTES		
Search Notes	Date	Examiner
PLUS	01/07/2008	SHK
Consultation with Scott Haugland	5/19/1008	SHK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
US PGPUBS		5/19/2008	SHK